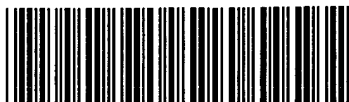


**Search Notes**

Application/Control No.

10/720,540

Examiner

David Buttner

Applicant(s)/Patent under  
Reexamination

HAYASHI ET AL.

Art Unit

1712

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
524	all	8/4/2006	DB
525	all	8/4/2006	DB
473	all	8/4/2006	DB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	8/4/2006	DB